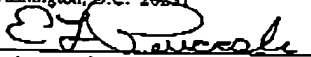


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Patent  
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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s):	Keeth, et al.	)	
Serial No.:	09/899,977	)	Examiner:
Filed:	07/06/2001	)	Art Unit: 2818
Entitled:	256 MEG DYNAMIC RANDOM ACCESS MEMORY		

### SECOND PRELIMINARY AMENDMENT

Preliminary to the examination of the above-identified application, please amend the claims as follows.

70. (Once Amended) A dynamic random access memory, comprising:  
an array of memory cells[, each comprised of two storage elements];  
a plurality of peripheral devices for writing data into said memory cells and for reading data out of said memory cells;

a plurality of voltage supplies responsive to an external voltage for generating a plurality of supply voltages for use by said array and said plurality of peripheral devices; and

test mode logic for determining whether the memory is in a test mode, and wherein said plurality of peripheral devices includes a [latch] latching circuit responsive to a first external signal when the memory is in the test mode, for latching data stored in a first seed group of memory elements, and [a write] an enable circuit responsive to a second external signal when said memory is in the test mode, for enabling the latched data to be written to a second group of memory elements.

71. (Once Amended) A method of testing a plurality of memory elements organized in a plurality of rows, comprising the steps of:

writing test data into a first seed row of memory elements;